



IN THE  
UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor(s): Benjamin T. Percer et al.

Confirmation No.: 5780

Application No.: 10/606,715

Examiner: LE, John H.

Filing Date: 06/26/2003

Group Art Unit: 2863

Title: METHODS AND SYSTEMS FOR MASKING FAULTS IN A MARGIN TESTING ENVIRONMENT

Commissioner for Patents  
PO Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

This Information Disclosure Statement is submitted:

- ( ) under 37 CFR 1.97(b), or  
(Within three months of filing national application; or date of entry of national application; or before mailing date of first office action on the merits; whichever occurs last)
- (X) under 37 CFR 1.97 (c) together with either a:  
( ) Statement under 37 CFR 1.97(e), or  
(X) a \$180.00 fee under 37 CFR 1.17(p), or  
(After the CFR 1.97 (b) time period, but before final action or notice of allowance, whichever occurs first)
- ( ) under 37 CFR 1.97 (d) together with a:  
( ) Statement under 37 CFR 1.97(e)(1) or (2), and  
( ) a \$180.00 fee set forth in 37 CFR 1.17(p).  
(Filed after final action, a notice of allowance, on or before payment of the issue fee)

Please charge to Deposit Account **08-2025** the sum of \$180.00. At any time during the pendency of this application, please charge any fees required or credit any overpayment to Deposit Account **08-2025** pursuant to 37 CFR 1.25.

(X) Applicant(s) submit herewith Form PTO 1449 - Information Disclosure Statement together with any required copies of patents, publications or other information of which applicant(s) are aware, which applicant(s) believe(s) may be material to the examination of this application and for which there may be a duty to disclose in accordance with 37 CFR 1.56.

(X) A concise explanation of the relevance of foreign language patents, foreign language publications and other foreign language information listed on PTO Form 1449, as presently understood by the individuals(s) designated in 37 CFR 1.56 (c) most knowledgeable about the content is given on the attached sheet, or where a foreign language patent is cited in a search report or other action by a foreign patent office in a counterpart foreign application, an English language version of the search report or action which indicates the degree of relevance found by the foreign office is listed on form PTO 1449 and is enclosed herewith.

It is requested that the information disclosed herein be made of record in this application.

( ) I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to:  
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Respectfully submitted,

Benjamin T. Percer et al.

By

Michael G. Verga, Esq.

Attorney/Agent for Applicant(s)  
Reg. No. 39,410

Date: 02-28-2005

Telephone No.: (703) 591-2644

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**PATENT APPLICATION**

Sheet 1 of 2

FORM PTO-1449

**LIST OF PATENTS AND PUBLICATIONS FOR  
APPLICANT'S INFORMATION DISCLOSURE  
STATEMENT**

(Use several sheets if necessary)

ATTY. DOCKET NO.

**200312936-1**

APPLICATION NO.

**10/606,715**

CONFIRMATION NO.

**5780**

APPLICANT

**Benjamin T. Percer et al.**

FILING DATE

**06-26-2003**

GROUP

**2863****REFERENCE DESIGNATION****U.S. PATENT DOCUMENTS**

EXAMINER INITIAL		DOCUMENT NUMBER	PUBLICATION DATE	NAME	Pages, Columns, Lines Where Relevant Passages or Figures Appear
	1A	5,157,326	Oct. 20, 1992	BURNSIDES	
	1B	6,476,615	Nov. 05, 2002	MARBOT ET AL.	
	1C	6,563,350	May 13, 2003	WARNER ET AL.	
	1D	6,564,350	May 13, 2003	HOEWELER	
	1E	6,697,952	Feb. 24, 2004	KING	
	1F				
	1G				
	1H				
	1I				
	1J				
	1K				

**FOREIGN PATENT DOCUMENTS**

		DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	Pages/Columns/Lines Where Relevant Passages/Figures Appear	Check if Translation attached
	1L	JP 62-262165	11-14-1987	NIPPON ELECTRIC		
	1M	EP 0 505 120	09-23-1992	AMDAHL		
	1N	JP 5-2502	01-08-1993	NIPPON ELECTRIC		
	1O	GB 1 219 001	01-13-1971	INDUSTRIAL NUCLEONIC		
	1P					

**OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)**

	1Q	Great Britain Search Report. Application No. GB0413503.4. October 27, 2004.
	1R	Great Britatin Search Report. Application No. GB0413502.6. November 9, 2004.
	1S	Great Britain Search Report. Application No. GB 0413501.8. November 5, 2004.

EXAMINER

DATE CONSIDERED

**PATENT APPLICATION**

Sheet 2 of 2

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**LIST OF PATENTS AND PUBLICATIONS FOR  
APPLICANT'S INFORMATION DISCLOSURE  
STATEMENT**

(Use several sheets if necessary)

ATTY. DOCKET NO.

**200208051-1**

APPLICATION NO.

**10/606,463**

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APPLICANT

**Benjamin T. Percer et al.**

FILING DATE

**06-26-2003**

GROUP

**2863****REFERENCE DESIGNATION****U.S. PATENT DOCUMENTS**

EXAMINER INITIAL		DOCUMENT NUMBER	PUBLICATION DATE	NAME	Pages, Columns, Lines Where Relevant Passages or Figures Appear
	2A				
	2B				
	2C				
	2D				
	2E				
	2F				
	2G				
	2H				
	2I				
	2J				
	2K				

**FOREIGN PATENT DOCUMENTS**

		DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	Pages/Columns/Lines Where Relevant Passages/Figures Appear	Check if Translation attached
	2L					
	2M					
	2N					
	2O					
	2P					

**OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)**

	2Q	Berner, et al. "DC Voltage Margin Tester. NB84092465. IBM Technical Disclosure Bulletin, Vol. 27, No. 4B, September 1984, pg. 246.
	2R	Tsukude, et al. "Highly Reliable Testing of ULSI Memories with On-Chip Voltage-Down Converters". IEEE Design & Test Computers. June 1993, pgs. 6-12.
	2S	

EXAMINER

DATE CONSIDERED